NOTES:

- 1. SUBSTRATE: UV FUSED SILICA
- 2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec

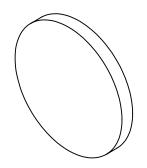
3. COATING (APPLY ACROSS COATING APERTURE)
S1: HARD DIELECTRIC SPUTTERED
T(avg): ≥91% FROM 790 - 1650nm @ 0° AOI
T(avg): ≤0.01% FROM 200 - 760nm @ 0° AOI
T(abs): =50% FOR 775±7.75nm @ 0° AOI

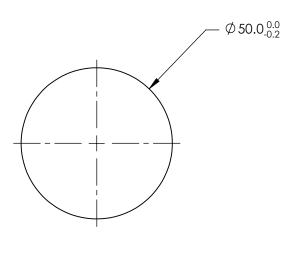
S2:SINGLE LAYER MgF2

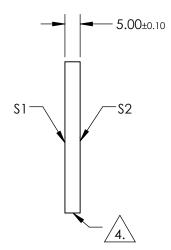
4. FINE GRIND SURFACE

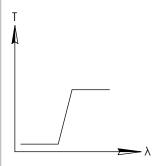
- 5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
- 6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm (prior to coating)
- 7. ROHS COMPLIANT











LONGPASS FILTER

	\$1	\$2
SHAPE	PLANO	PLANO
SURFACE QUALITY	60-40	60-40
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE DIMENSIONS ARE FOR REFERENCE ONLY

Edmund Optics®

THIRD ANGLE PROJECTION		TITLE	Ø50mm, 775nm, HIGH PERFORMANCE LONGPASS FILTER	
ALL DIMS IN	mm	DWG NO	86077 SHEET 1 OF 1	